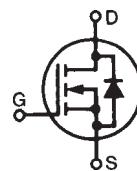


PolarHV™ HiPerFET Power MOSFET

N-Channel Enhancement Mode
Avalanche Rated
Fast Intrinsic Diode

IXFK 48N60P IXFX 48N60P

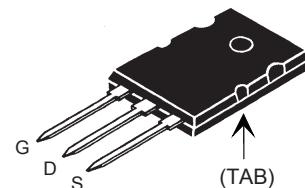
V_{DSS}	=	600 V
I_{D2}	=	48 A
$R_{DS(on)}$	\leq	135mΩ
t_{rr}	\leq	200 ns



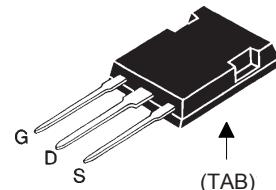
Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ C$ to $150^\circ C$	600		V
V_{DGR}	$T_J = 25^\circ C$ to $150^\circ C$; $R_{GS} = 1 M\Omega$	600		V
V_{GSS}	Continuous	± 30		V
V_{GSM}	Transient	± 40		V
I_{D25}	$T_c = 25^\circ C$	48		A
I_{DM}	$T_c = 25^\circ C$, pulse width limited by T_{JM}	110		A
I_{AR}	$T_c = 25^\circ C$	48		A
E_{AR}	$T_c = 25^\circ C$	70		mJ
E_{AS}	$T_c = 25^\circ C$	2.0		J
dv/dt	$I_s \leq I_{DM}$, $di/dt \leq 100 A/\mu s$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ C$, $R_G = 4 \Omega$	20	V/ns	
P_D	$T_c = 25^\circ C$	830		W
T_J		-55 ... +150		°C
T_{JM}		150		°C
T_{stg}		-55 ... +150		°C
M_d	Mounting torque (TO-264)	1.13/10 Nm/lb.in.		
Weight	TO-264	10		g
	PLUS247	6		g
T_L	1.6 mm (0.062 in.) from case for 10 s	300		°C
T_{sOLD}	Plastic body for 10 s	260		°C

Symbol	Test Conditions ($T_J = 25^\circ C$, unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
BV_{DSS}	$V_{GS} = 0 V$, $I_D = 250 \mu A$	600		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 8 mA$	3.0	5.0	V
I_{GSS}	$V_{GS} = \pm 30 V_{DC}$, $V_{DS} = 0$		± 200	nA
I_{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0 V$	$T_J = 125^\circ C$	25 1000	μA
$R_{DS(on)}$	$V_{GS} = 10 V$, $I_D = 0.5 I_{D25}$ Pulse test, $t \leq 300 \mu s$, duty cycle $d \leq 2 \%$		135	mΩ

TO-264 (IXFK)



PLUS247 (IXFX)



G = Gate D = Drain
S = Source Tab = Drain

Features

- International standard packages
- Fast recovery diode
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
 - easy to drive and to protect

Advantages

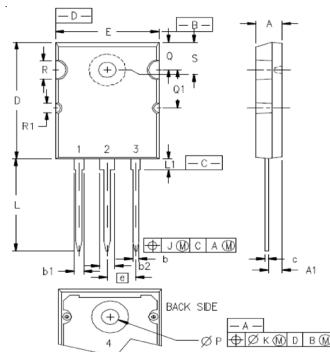
- Easy to mount
- Space savings
- High power density

Symbol **Test Conditions**
Characteristic Values
 $(T_J = 25^\circ C, \text{ unless otherwise specified})$
Min. **Typ.** **Max.**

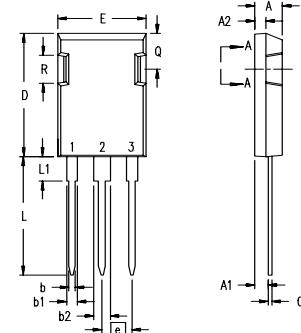
g_{fs}	$V_{DS} = 20 V; I_D = 0.5 I_{D25}$, pulse test	35	53	S
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0 V, V_{DS} = 25 V, f = 1 \text{ MHz}$	8860	pF	
		850	pF	
		60	pF	
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	$V_{GS} = 10 V, V_{DS} = 0.5 I_{D25}$ $R_G = 2 \Omega$ (External)	30	ns	
		25	ns	
		85	ns	
		22	ns	
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10 V, V_{DS} = 0.5 V_{DSS}, I_D = 0.5 I_{D25}$	150	nC	
		50	nC	
		50	nC	
R_{thJC}	TO-264 and PLUS247	0.15	$^\circ C/W$	
R_{thCs}				
		0.15	$^\circ C/W$	

Source-Drain Diode
Characteristic Values
 $(T_J = 25^\circ C, \text{ unless otherwise specified})$
Symbol **Test Conditions**
Min. **Typ.** **Max.**

I_s	$V_{GS} = 0 V$		48	A
I_{SM}	Repetitive		110	A
V_{SD}	$I_F = I_s, V_{GS} = 0 V$, Pulse test, $t \leq 300 \mu s$, duty cycle $d \leq 2\%$		1.5	V
t_{rr} Q_{RM}	$I_F = 25 A, -di/dt = 100 A/\mu s$ $V_R = 100 V$	200	ns	
		0.8	μC	
		6.0	A	

TO-264 (IXFK) Outline

 1 - GATE
 2, 4 - DRAIN (COLLECTOR)
 3 - SOURCE (EMITTER)

SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.185	.209	4.70	5.31
A1	.102	.118	2.59	3.00
b	.037	.055	0.94	1.40
b1	.087	.102	2.21	2.59
b2	.110	.126	2.79	3.20
c	.017	.029	0.43	0.74
D	1.007	1.047	25.58	26.59
E	.760	.799	19.30	20.29
e	.215 BSC		5.46 BSC	
J	.000	.010	0.00	0.25
K	.000	.010	0.00	0.25
L	.779	.842	19.79	21.39
L1	.087	.102	2.21	2.59
$\emptyset P$.122	.138	3.10	3.51
Q	.240	.256	6.10	6.50
Q1	.330	.346	8.38	8.79
$\emptyset R$.155	.187	3.94	4.75
$\emptyset R1$.085	.093	2.16	2.36
S	.243	.253	6.17	6.45

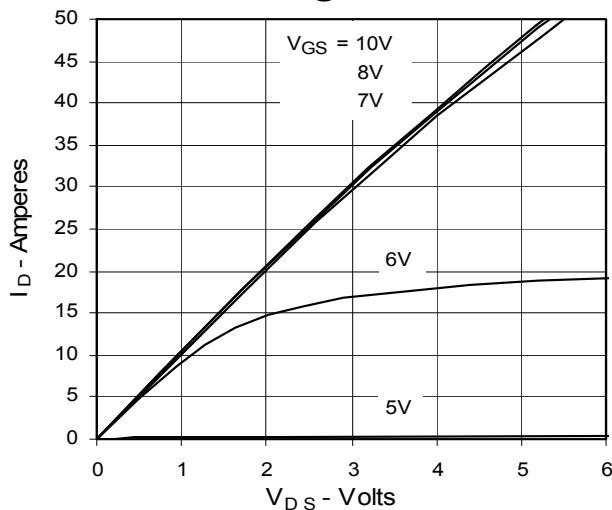
PLUS 247™ (IXFX) Outline

 Terminals:
 1 - Gate
 2 - Drain (Collector)
 3 - Source (Emitter)
 4 - Drain (Collector)

Dim.	Millimeter Min.	Max.	Inches Min.	Max.
A	4.83	5.21	.190	.205
A ₁	2.29	2.54	.090	.100
A ₂	1.91	2.16	.075	.085
b	1.14	1.40	.045	.055
b ₁	1.91	2.13	.075	.084
b ₂	2.92	3.12	.115	.123
C	0.61	0.80	.024	.031
D	20.80	21.34	.819	.840
E	15.75	16.13	.620	.635
e	5.45 BSC		.215 BSC	
L	19.81	20.32	.780	.800
L1	3.81	4.32	.150	.170
Q	5.59	6.20	.220	.244
R	4.32	4.83	.170	.190

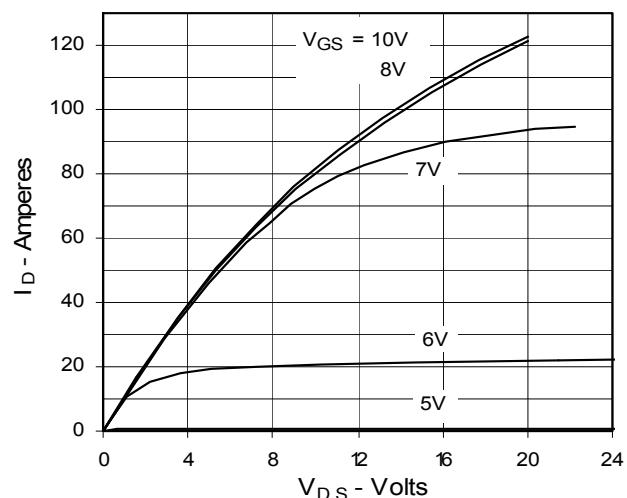
IXYS reserves the right to change limits, test conditions, and dimensions.

 IXYS MOSFETs and IGBTs are covered by 4,835,592 4,931,844 5,049,961 5,237,481 6,162,665 6,404,065 B1 6,683,344 6,727,585
 one or more of the following U.S. patents: 4,850,072 5,017,508 5,063,307 5,381,025 6,259,123 B1 6,534,343 6,710,405B2 6,759,692
 4,881,106 5,034,796 5,187,117 5,486,715 6,306,728 B1 6,583,505 6,710,463 6,771,478 B2

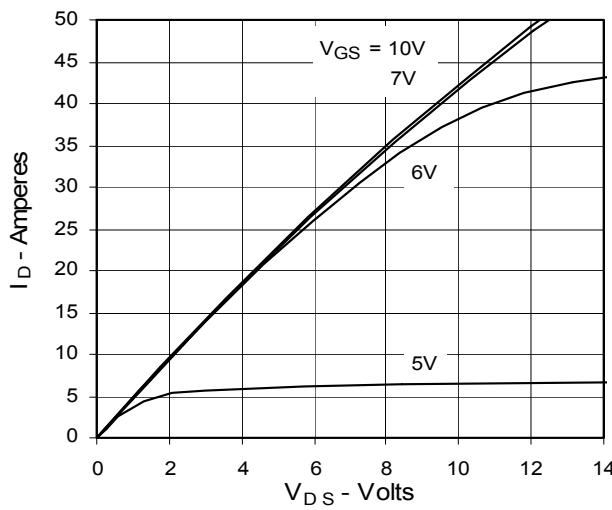
**Fig. 1. Output Characteristics
@ 25°C**



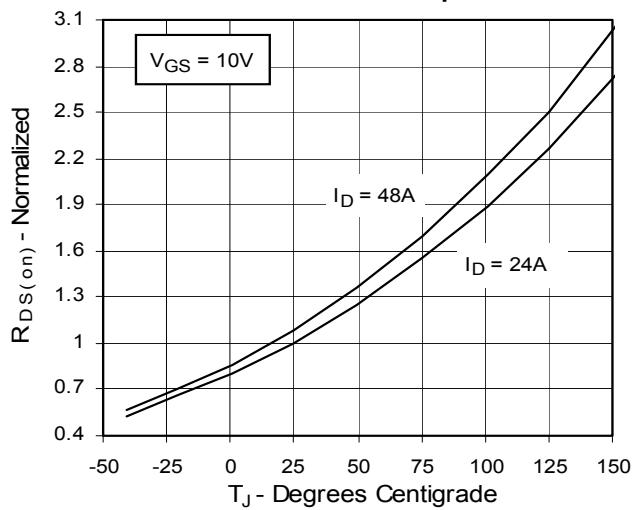
**Fig. 2. Extended Output Characteristics
@ 25°C**



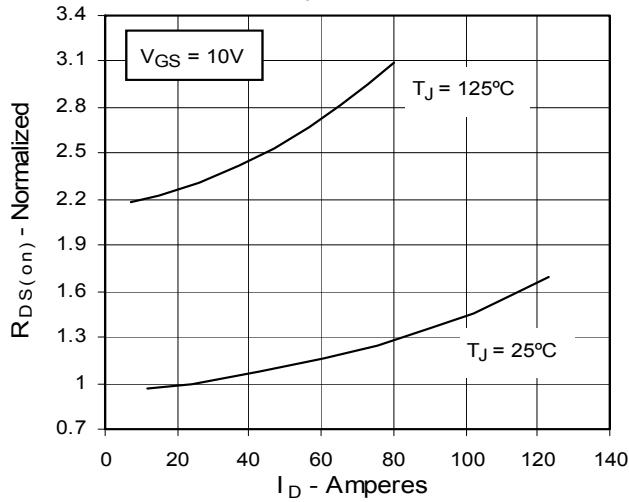
**Fig. 3. Output Characteristics
@ 125°C**



**Fig. 4. $R_{DS(on)}$ Normalized to 0.5 I_{D25}
Value vs. Junction Temperature**



**Fig. 5. $R_{DS(on)}$ Normalized to
0.5 I_{D25} Value vs. I_D**



**Fig. 6. Drain Current vs. Case
Temperature**

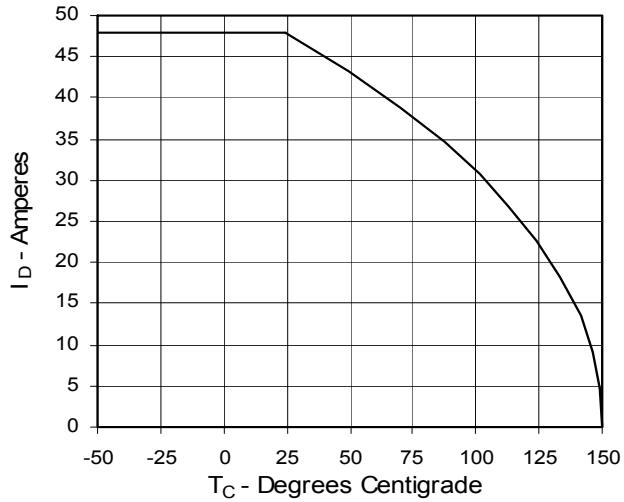
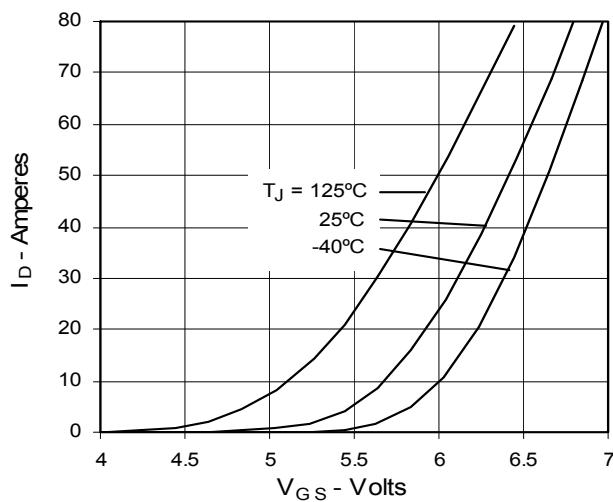
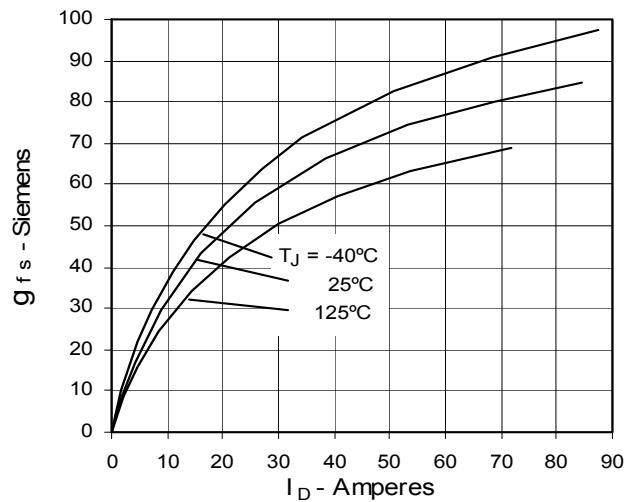
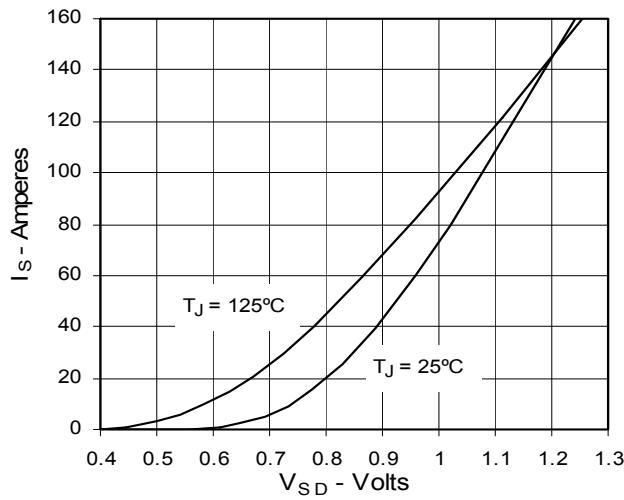
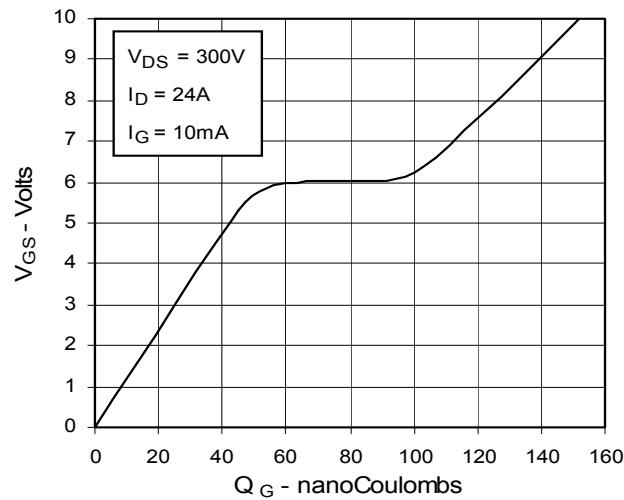
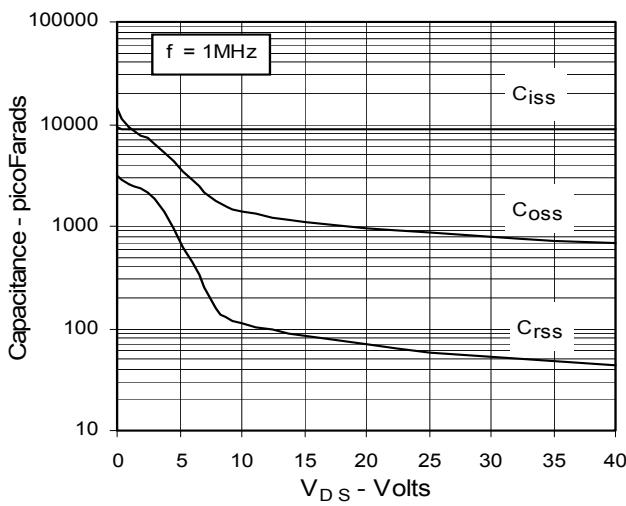
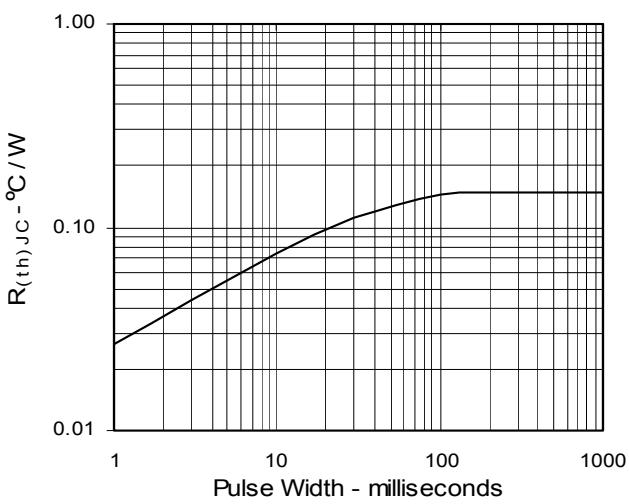


Fig. 7. Input Admittance

Fig. 8. Transconductance

Fig. 9. Source Current vs. Source-To-Drain Voltage

Fig. 10. Gate Charge

Fig. 11. Capacitance

Fig. 13. Maximum Transient Thermal Resistance




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